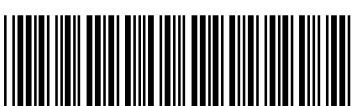


<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10590585	TAKAHASHI ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	David K O'Dell	1625

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
546	148, 177, 178, 179, 196, 200	02/24/2010	dko
544	363	02/24/2010	dko
546	17, 126, 153	8/10/2010	dko
514	278, 304, 312	8/10/2010	dko

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
STN, EAST, PALM	02/24/2010	dko
EAST, PALM	8/10/2010	dko
Patentability Conference	08/9/2010	dko

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
546	17, 126, 153	8/10/2010	dko
514	278, 304, 312	8/10/2010	dko

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Examiner.Art Unit 1625